

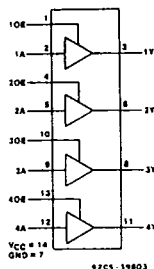
CD54/74HC126
CD54/74HCT126

File Number 1772

HARRIS SEMICONDUCTOR

27E D ■ 430227J 0017567 T ■ HAS

High-Speed CMOS Logic



Quad Buffer; 3-State

Type Features:

- Separate output enable inputs
- 3-state outputs

FUNCTIONAL DIAGRAM

The RCA CD54/74HC126 and CD54/74HCT126 contain four independent 3-state buffers, each having its own output enable input, which when "low" puts the output in the high-impedance state.

The CD54HC/HCT126 are supplied in 14-lead hermetic dual-in-line ceramic packages (F suffix). The CD74HC/HCT126 are supplied in 14-lead dual-in-line plastic packages (E suffix) and in 14-lead dual-in-line surface mount plastic packages (M suffix). Both types are also available in chip form (H suffix).

Family Features:

- Fanout (Over Temperature Range):
Standard Outputs - 10 LSTTL Loads
Bus Driver Outputs - 15 LSTTL Loads
- Wide Operating Temperature Range:
CD74HC/HCT/HCU: -40 to +85°C
- Balanced Propagation Delay and Transition Times
- Significant Power Reduction Compared to LSTTL Logic ICs
- Alternate Source is Philips/Signetics
- CD54HC/CD74HC Types:
2 to 6 V Operation
High Noise Immunity:
 $N_{IL} = 30\%$, $N_{IH} = 30\%$ of V_{CC} ; @ $V_{CC} = 5 V$
- CD54HCT/CD74HCT Types:
4.5 to 5.5 V Operation
Direct LSTTL Input Logic Compatibility
 $V_{IL} = 0.8 V$ Max., $V_{IH} = 2 V$ Min.
CMOS Input Compatibility $I_i \leq 1 \mu A$ @ V_{OL} , V_{OH}

TRUTH TABLE

Inputs		Outputs
nA	nOE	nY
H	H	H
L	H	L
X	L	Z

H = High Level
L = Low Level
X = Don't Care
Z = High Impedance (Off-State)

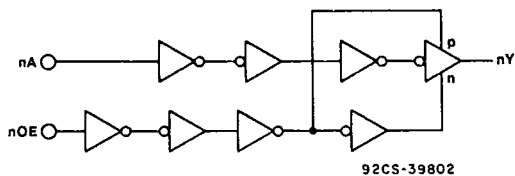


Fig. 1 - Logic Diagram

CD54/74HC126
CD54/74HCT126

MAXIMUM RATINGS, Absolute-Maximum Values:

DC SUPPLY-VOLTAGE, (V_{CC}):
(Voltages referenced to ground) -0.5 to +7 V

DC INPUT DIODE CURRENT, I_{IK} (FOR $V_i < -0.5$ V OR $V_i > V_{CC} + 0.5$ V) ± 20 mA

DC OUTPUT DIODE CURRENT, I_{OK} (FOR $V_o < -0.5$ V OR $V_o > V_{CC} + 0.5$ V) ± 20 mA

DC DRAIN CURRENT, PER OUTPUT (I_o) (FOR -0.5 V $< V_o < V_{CC} + 0.5$ V) ± 35 mA

DC V_{CC} OR GROUND CURRENT (I_{CC}) ± 70 mA

POWER DISSIPATION PER PACKAGE (P_D):
For $T_A = -40$ to $+60^\circ\text{C}$ (PACKAGE TYPE E) 500 mW
For $T_A = +60$ to $+85^\circ\text{C}$ (PACKAGE TYPE E) Derate Linearly at 8 mW/ $^\circ\text{C}$ to 300 mW
For $T_A = -55$ to $+100^\circ\text{C}$ (PACKAGE TYPE F, H) 500 mW
For $T_A = +100$ to $+125^\circ\text{C}$ (PACKAGE TYPE F, H) Derate Linearly at 8 mW/ $^\circ\text{C}$ to 300 mW
For $T_A = -40$ to $+70^\circ\text{C}$ (PACKAGE TYPE M) 400 mW
For $T_A = +70$ to $+125^\circ\text{C}$ (PACKAGE TYPE M) Derate Linearly at 6 mW/ $^\circ\text{C}$ to 70 mW

OPERATING-TEMPERATURE RANGE (T_A):
PACKAGE TYPE F, H -55 to $+125^\circ\text{C}$
PACKAGE TYPE E, M -40 to $+85^\circ\text{C}$

STORAGE TEMPERATURE (T_{STG}) -65 to $+150^\circ\text{C}$

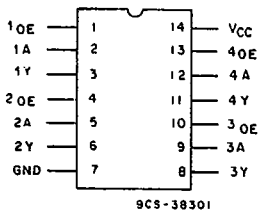
LEAD TEMPERATURE (DURING SOLDERING):
At distance $1/16 \pm 1/32$ in. (1.59 ± 0.79 mm) from case for 10 s max. $+265^\circ\text{C}$
Unit inserted into a PC Board (min. thickness $1/16$ in., 1.59 mm)
with solder contacting lead tips only $+300^\circ\text{C}$

RECOMMENDED OPERATING CONDITIONS:

For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTIC	LIMITS		UNITS
	MIN.	MAX.	
Supply-Voltage Range (For $T_A =$ Full Package-Temperature Range) V_{CC} .* CD54/74HC Types CD54/74HCT Types	2 4.5	6 5.5	V
DC Input or Output Voltage V_i, V_o	0	V_{CC}	V
Operating Temperature T_A : CD74 Types CD54 Types	-40 -55	+85 +125	$^\circ\text{C}$
Input Rise and Fall Times t_r, t_f at 2 V at 4.5 V at 6 V	0 0 0	1000 500 400	ns

*Unless otherwise specified, all voltages are referenced to Ground.



TERMINAL ASSIGNMENT

HARRIS SEMICONDUCTOR SECTOR 27E D 4302271 0017568 J HAS

CD54/74HC126
CD54/74HCT126

STATIC ELECTRICAL CHARACTERISTICS

CHARACTERISTIC	CD74HC126/CD54HC126										CD74HCT126/CD54HCT126										UNITS										
	TEST CONDITIONS			74HC/54HC TYPES			74HC TYPE		54HC TYPE		TEST CONDITIONS		74HCT/54HCT TYPES			74HCT TYPE		54HCT TYPE													
	V _I V	I _O mA	V _{CC} V	+25°C			-40/ +85°C		-55/ +125°C		V _I V	V _{CC} V	+25°C			-40/ +85°C		-55/ +125°C													
				Min	Typ	Max	Min	Max	Min	Max			Min	Typ	Max	Min	Max	Min	Max												
High-Level Input Voltage V _{IH}			2	1.5	—	—	1.5	—	1.5	—	—	4.5									V										
			4.5	3.15	—	—	3.15	—	3.15	—	—	to	2	—	—	2	—	2	—	—											
			6	4.2	—	—	4.2	—	4.2	—	—	5.5																			
Low-Level Input Voltage V _{IL}			2	—	—	0.5	—	0.5	—	0.5	—	4.5									V										
			4.5	—	—	1.35	—	1.35	—	1.35	—	to	—	—	0.8	—	0.8	—	0.8	—		0.8									
			6	—	—	1.8	—	1.8	—	1.8	—	5.5																			
High-Level Output Voltage V _{OH}	V _{IL}	-0.02	2	1.9	—	—	1.9	—	1.9	—	V _{IL}	4.5	4.4	—	—	4.4	—	4.4	—	4.4	—	V									
	or		4.5	4.4	—	—	4.4	—	4.4	—	or												4.4	—	—	4.4	—	4.4	—	4.4	—
	CMOS Loads V _{IH}		6	5.9	—	—	5.9	—	5.9	—	V _{IH}																				
TTL Loads (Bus Driver)	V _{IL}	-7.8	6	5.48	—	—	5.34	—	5.2	—	V _{IL}	4.5	3.98	—	—	3.84	—	3.7	—	3.7	—	V									
	or		4.5	3.98	—	—	3.84	—	3.7	—	or												3.98	—	—	3.84	—	3.7	—	3.7	—
	V _{IH}		6	5.48	—	—	5.34	—	5.2	—	V _{IH}																				
Low-Level Output Voltage V _{OL}	V _{IL}	0.02	2	—	—	0.1	—	0.1	—	0.1	V _{IL}	4.5	—	—	0.1	—	0.1	—	0.1	—	0.1	V									
	or		4.5	—	—	0.1	—	0.1	—	0.1	—												or	—	—	0.1	—	0.1	—	0.1	—
	CMOS Loads V _{IH}		6	—	—	0.1	—	0.1	—	0.1	—												V _{IH}								
TTL Loads (Bus Driver)	V _{IL}	6	4.5	—	—	0.26	—	0.33	—	0.4	V _{IL}	4.5	—	—	0.26	—	0.33	—	0.4	—	0.4	V									
	or		4.5	—	—	0.26	—	0.33	—	0.4	—												—	—	0.26	—	0.33	—	0.4	—	
	V _{IH}		7.8	6	—	—	0.26	—	0.33	—	0.4												V _{IH}								
Input Leakage Current I _I	V _{CC}	6	—	—	±0.1	—	±1	—	±1	—	Any Voltage Between V _{CC} and Gnd	5.5	—	—	±0.1	—	±1	—	±1	—	±1	μA									
	or		6	—	—	±0.1	—	±1	—	±1													—								
	Gnd		6	—	—	±0.1	—	±1	—	±1													—								
Quiescent Device Current I _{CC}	V _{CC}	0	6	—	—	8	—	80	—	160	V _{CC}	5.5	—	—	8	—	80	—	160	—	160	μA									
	or		6	—	—	8	—	80	—	160	or												—	—	8	—	80	—	160	—	160
	Gnd		6	—	—	8	—	80	—	160	Gnd												—	—	8	—	80	—	160	—	160
Additional Quiescent Device Current per input pin, 1 unit load ΔI _{CC} *											V _{CC} -2.1	4.5 to 5.5	—	100	360	—	450	—	490	—	490	μA									
	3-State Leakage Current I _{OZ}	V _{IL} or V _{IH}	V _O =V _{CC} or Gnd	6	—	—	±0.5	—	±5	—	±10	V _{IL} or V _{IH}	5.5	—	—	±0.5	—	±5	—	±10	—	±10	μA								

* For dual-supply systems theoretical worst case (V_I = 2.4 V, V_{CC} = 5.5 V) specification is 1.8 mA.

HCT Input Loading Table

Input	Unit Loads*
nA, nOE	1

*Unit Load is ΔI_{CC} limit specified in Static Characteristics Chart, e.g., 360 μA max. @ 25°C.

HARRIS SEMICONDUCTOR 27E D 430227J 0017569 3 HAS

CD54/74HC126 CD54/74HCT126

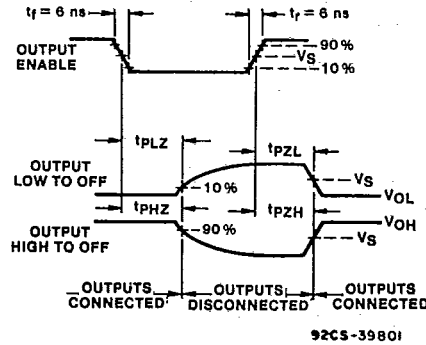
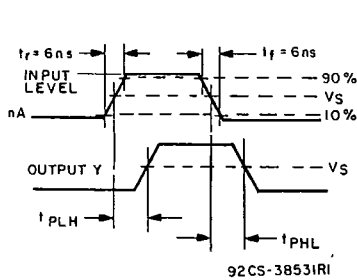
SWITCHING CHARACTERISTICS ($V_{CC}=5\text{ V}$, $T_A=25^\circ\text{C}$, Input t_r , $t_f=6\text{ ns}$)

CHARACTERISTIC	C_L pF	SYMBOL	TYPICAL		UNITS
			HC	HCT	
Propagation Delay Data to Outputs	15	t_{PHL} , t_{PLH}	8	9	ns
Output Enabling Time	15	t_{PZL} , t_{PZH}	10	10	
Output Disabling Time	15	t_{PLZ} , t_{PHZ}	10	11	
Power Dissipation Capacitance*	—	C_{PD}	30	36	pF

* C_{PD} is used to determine the dynamic power consumption, per multiplexer.
 $P_D = V_{CC}^2 f_i (C_{PD} + C_L)$ where: f_i =input frequency
 C_L =load capacitance
 V_{CC} =supply voltage

SWITCHING CHARACTERISTICS ($C_L=50\text{ pF}$, Input t_r , $t_f=6\text{ ns}$)

CHARACTERISTIC	SYMBOL	V_{CC}	25°C				-40°C to +85°C				-55°C to +125°C				UNITS
			HC		HCT		74HC		74HCT		54HC		54HCT		
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Propagation Delay Data to Outputs	t_{PLH} t_{PHL}	2	—	100	—	—	—	125	—	—	—	150	—	—	ns
		4.5	—	20	—	24	—	25	—	30	—	30	—	36	
		6	—	17	—	—	—	21	—	—	—	36	—	—	
Enable Delay Times	t_{PZH} t_{PZL}	2	—	125	—	—	—	155	—	—	—	190	—	—	ns
		4.5	—	25	—	25	—	31	—	31	—	38	—	38	
		6	—	21	—	—	—	26	—	—	—	32	—	—	
Disable Delay Times	t_{PHZ} t_{PLZ}	2	—	125	—	—	—	155	—	—	—	190	—	—	ns
		4.5	—	25	—	28	—	31	—	35	—	38	—	42	
		6	—	21	—	—	—	26	—	—	—	32	—	—	
Output Transition Time	t_{TLH} t_{THL}	2	—	60	—	—	—	75	—	—	—	90	—	—	ns
		4.5	—	12	—	12	—	15	—	15	—	18	—	18	
		6	—	10	—	—	—	13	—	—	—	15	—	—	
Input Capacitance	C_i	—	—	10	—	10	—	10	—	10	—	10	—	10	pF
3-State Output Capacitance	C_o	—	—	20	—	20	—	20	—	20	—	20	—	20	



	54/74HC	54/74HCT
Input Level	V_{CC}	3 V
Switching Voltage, V_s	50% V_{CC}	1.3 V

Fig. 2 — Transition and propagation delay times.

CD54/74HC126
CD54/74HCT126

HARRIS SEMICONDUCTOR SECTOR

27E D ■ 4302271 0017571 1 ■ HAS

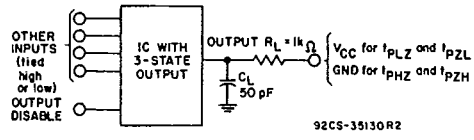


Fig. 3 - Three-state propagation delay test circuit.